

From the DASN (A&LM) Office Mike Howard, DON IUID/SIM Champion



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elcome to the December 2010 issue of the *DON IUID Journal*. As the DON IUID/SIM Champion, I want to thank you, the IUID Community, for your continued support of the *DON IUID Journal*.

When it comes to implementation of IUID, many people have expressed concerns about the cost involved. Keeping marking costs down is key to the success of the IUID program, which is one reason that SECNAVINST 4440.34 has specifically identified opportunistic marking the preferred approach. Because it is so important that we get as much “bang for the buck” as we can, I have determined that the next DON IUID Training Symposium (DIETS 4) will focus on “Making Every Dollar Count.” Topics to be addressed at DIETS 4 include:

- DON Marking Guide and Independent Government Cost Estimates
- Reducing Non-Recurring Engineering Costs: Shape Search Software for Label Updates Pilot
- DON Low-Cost Marking in Action: SPAWAR Kitting, US Marine Corps Search & Apply, and Depot Marking

DIETS 4 will be held January 11-13, 2011 in San Diego, CA. I strongly encourage you to attend to further your knowledge regarding cost-effective IUID marking and business systems enablement. As of this writing, confirmed speakers include Ms. LeAntha Sumpter, SES, Deputy Director, Program Development and Implementation (OSD DPAP), RMDL David Baucom, DASN (A&LM), Mr. Dennis Taitano, SES, DASN (FM&C), CAPT Jerry Reid, Director of Logistics, DASN (A&LM); and MAJ Brian Spooner, IUID Lead for US Marine Corps.

Harnessing the power of IUID through business systems integration continues to be a top priority for DON IUID implementation. This issue includes an article on the recent enablement of the Product Data Reporting and Evaluation Program (PDREP) for deficiency reporting, and a low-cost approach to AIS IUID implementation that will be presented at DIETS 4. DASN (A&LM) is developing an additional low-cost approach for ERP enablement, in concert with OPNAV N40.

Our goal in publishing this journal is twofold: (1) we want to disseminate information that will enable you to achieve success in your compliance efforts and (2) we want to be your “go-to” resource for DON IUID-related information. As I have stated in previous issues of the *DON IUID Journal*, to reach our goals, we need your input. We welcome all input from all members of the community—be it articles for submission, advice to others, implementation-related SYSCOM news, or questions you might have.

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